

orm PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1680SERIAL NO.
09/875,664LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)

MAY 10 2002

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PATENT & TRADEMARK OFFICEAPPLICANT
Micron Technology, Inc.FILING DATE
April 3, 2001GROUP
7858

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA	5,886,863	3/23/1999	Nagasaki et al.			
	AB						
	AC						
	AD						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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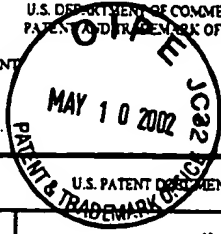
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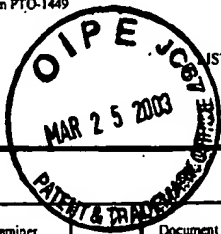
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1680		SERIAL NO. 09/823,664	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT David R. Hembree		FILING DATE April 3, 2001	
				GROUP 2838			
							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
VN	AA 3,440,407	4/22/69	Goltsos et al.				
	AB 3,614,343	10/19/71	Quinn				
	AC 3,683,306	8/8/72	Bulthuis et al.				
	AD 4,332,081	6/1/82	Francis				
	AE 4,318,944	3/21/83	Faris				
	AF 4,703,555	11/3/87	Hubner				
	AG 3,141,334	8/23/92	Castles				
	AH 3,347,869	9/20/94	Shie et al.				
	AI 3,406,109	4/11/95	Whitney				
	AJ 3,436,646	7/25/95	McArthur et al.				
	AK 3,446,437	8/29/95	Bentien et al.				
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
VN	AL 2336778	7/1977	France				
VN	AM 16-12521	2/1981	Kobayashi, Japan				
VN	AN 1-268462	11-1990	Yamanishi, Japan				
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
VN	AR	✓	Application On-Board Temperature Sensors, Watlow Electrical Manufacturing Company Catalog, pp. 773-778, 1992/1993.				
VN	AS	✓	In-Situ Survey System of Resistive and Thermoelectric Properties of Either Pure or Mixed Materials in Thin Films Evaporated Under Ultra High Vacuum, Schvettler, Leffebvre, Richon, Serron, & Gosselin, J. Phys. III France, Vol. 2, pp. 409-416, 94/95 (Abstract only).				
VN	AT	✓	Temperature Metrology for CD Control in DUV Lithography, Jeffrey Parker and Wayne Reichen, pp. 111-112, 114, 116, 09/17/97.				
EXAMINER			DATE CONSIDERED				
mk Nguyen			03/12/04				
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)								
				APPLICANT David Hembree				
				FILING DATE April 3, 2001		GROUP 2858		
PATENT DOCUMENTS								
Examiner Initial	Class	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
VW	AA	5,612,574	3/18/97	Summorfelt et al.				
	AB	5,719,333	2/17/98	Hosoi et al.				
	AC	5,831,333	11/3/98	Malladi et al.				
	AD	5,919,548	7/6/99	Barton et al.				
	AE	5,331,283	9/2/96	Manaka et al.				
	AF	5,492,011	2/20/96	Amano et al.				
	AG							
AH								
AJ								
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AK							
	AL							
	AM							
	AN							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
VW	AP		"NTC and PTC Thermistors"; http://www.thermodisc.com/ntcptc.html ; 1/7/98; 2 pages.					
	AR		"DI-1B33 Linearized 4-Wire RTD Input"; http://www.dataq.com/d5b33.html ; 1/7/98; 2 pages.					
	AS		"RTD"; http://www.mtsensors.com/rtds.html ; 1/7/98; 3 pages.					
	AT		"Low Cost Thermal-Ribbon (TM) uses thin film RTD"; http://www.minco.com/s17624nr.html ; 1/7/98; 1 page.					
	AU		"Silicon Processing for the VLSI Era"; Volume 1 - Process Technology, Second Edition; S. Wolf et al.; 2000; pps 22-25 and pps. 841-845.					
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				LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)			
APPLICANT Micron Technology, Inc.				FILING DATE April 3, 2001		GROUP 2858	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
VN	AA	4,912,600	3/1990	Jaeger et al.	361	700	
↓	AB	5,436,494	7/1995	Mosihi	257	467	
↓	AC	5,969,639	10/1999	Lauf et al.	340	870.17	
	AD						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
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EXAMINER <i>mark Nguyen</i>				DATE CONSIDERED <i>03/12/04</i>			
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Micron Technology, Inc.FILING DATE
April 3, 2001GROUP
2858

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA	4,355,463	10/26/1982	Burns			
	AB						
	AC						
	AD						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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EXAMINER

mh Nguyen

DATE CONSIDERED

03/12/04

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JAN-16-2004 11:39

WELLS ST. JOHN, P.S.

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1680		SERIAL NO. 098383424	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micro Technology, Inc.			
				FILING DATE April 2, 2001		GROUP 2858	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subject	Filing Date If Appropriate
VN	AA	6,020,750	2/1/2000	Burger et al.			
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